

Notice of References Cited	Application/Control No. 10/529,682		Applicant(s)/Patent Under Reexamination MAACK, HANNS-INGO	
	Examiner JAYESH A. PATEL		Art Unit 2624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,921,200	07-2005	Booyesen et al.	378/205
*	B	US-2003/0016301	01-2003	Aizaki et al.	348/345
*	C	US-5,844,242	12-1998	Jalink et al.	250/370.09
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.